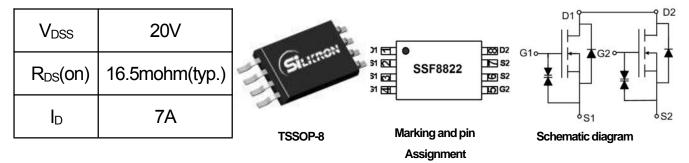


SSF8822

Main Product Characteristics:



Features and Benefits:

- Advanced MOSFET process technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 150°C operating temperature
- 2KV ESD Protected



Description:

It utilizes the latest processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications

Absolute max Rating:

Symbol	Parameter	Max.	Units
I _D @ TC = 25°C	Continuous Drain Current, V _{GS} @ 10V①	7	_
I _{DM}	Pulsed Drain Current2	25	A
P _D @TC = 25°C	Power Dissipation3	1.5	W
V _{DS}	Drain-Source Voltage	20	V
V _{GS}	Gate-to-Source Voltage	± 12	V
T _J T _{STG}	Operating Junction and Storage Temperature Range	-55 to +150	°C

Thermal Resistance

Symbol	Characterizes	Тур.	Max.	Units
R _{0JA}	Junction-to-ambient (t ≤ 10 s) ④	_	83	°C/W



Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
V _{(BR)DSS}	Drain-to-Source breakdown voltage	20		_	V	V _{GS} = 0V, ID = 250µA
			16.5	22	mΩ	V _{GS} =4.5V,I _D = 6.5A
D			17	23		V _{GS} =4V,I _D = 6A
RDS(on)	Static Drain-to-Source on-resistance		19	26		V _{GS} =3.1V,I _D = 5.5A
			22	30		V _{GS} =2.5V,I _D = 5.5A
V _{GS(th)}	Gate threshold voltage	0.6	0.75	1.2	V	$V_{DS} = V_{GS}, I_D = 250 \mu A$
I _{DSS}	Drain-to-Source leakage current	_		1	μA	V _{DS} = 20V,V _{GS} = 0V
I _{GSS} Gate-to-Source f	Cata ta Cauraa famuard laakara	_		±200	nA	V _{GS} =±4.5V,V _{DS} =0V
	Gate-to-Source forward leakage	_		±10	uA	V _{GS} =±10V,V _{DS} =0V
g fs	Forward Transconductance		6.6		S	V _{DS} =10V,I _D =6.5A
Qg	Total gate charge		10	15		V _{DS} =10V,
Q _{gs}	Gate-to-Source charge		2.3		nC	I _D =7A,
Q _{gd}	Gate-to-Drain("Miller") charge	_	3	_		V _{GS} =4.5V
t _{d(on)}	Turn-on delay time		10	20		
tr	Rise time	_	11	25]	V _{DD} =10V,I _D =1A
t _{d(off)}	Turn-Off delay time		35	70	ns	V_{GS} =4.5V, R_{GEN} =6 Ω
t _f	Fall time	_	30	60	1	
Ciss	Input capacitance	_	600	_		V _{GS} = 0V
Coss	Output capacitance	_	330		pF	V _{DS} = 8V
C _{rss}	Reverse transfer capacitance		140	_	1	f = 1.0MHz

Electrical Characterizes @TA=25°C unless otherwise specified

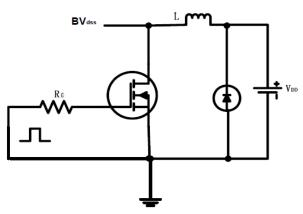
Source-Drain Ratings and Characteristics

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
	Continuous Source Current		_	7	A	MOSFET symbol
Is	(Body Diode)	_				showing the
	Pulsed Source Current			25	Δ	integral reverse
I _{SM}	(Body Diode)	_	_	25	A	p-n junction diode.
V _{SD}	Diode Forward Voltage	_	0.84	1.2	V	I _S =1.5A, V _{GS} =0V

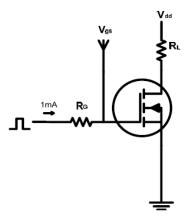


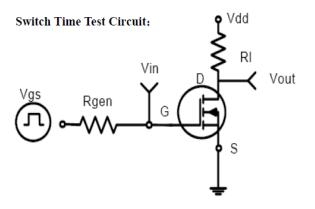
Test circuits and Waveforms

EAS test circuits:

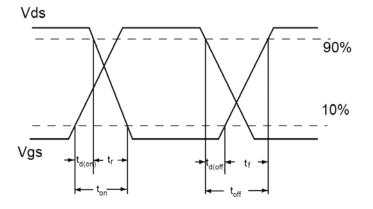


Gate charge test circuit:





Switch Waveforms:



Notes:

①Calculated continuous current based on maximum allowable junction temperature.

②Repetitive rating; pulse width limited by max. junction temperature.

- ③The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.
- (4) The value of $R_{\theta JA}$ is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with TA =25°C



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Typical electrical and thermal characteristics

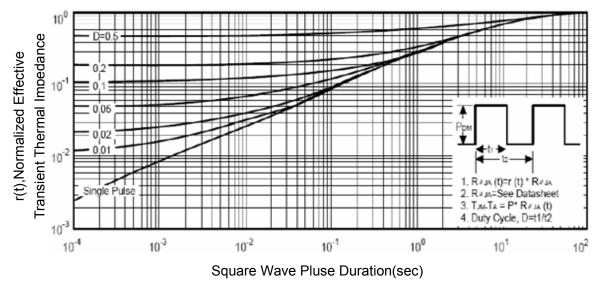
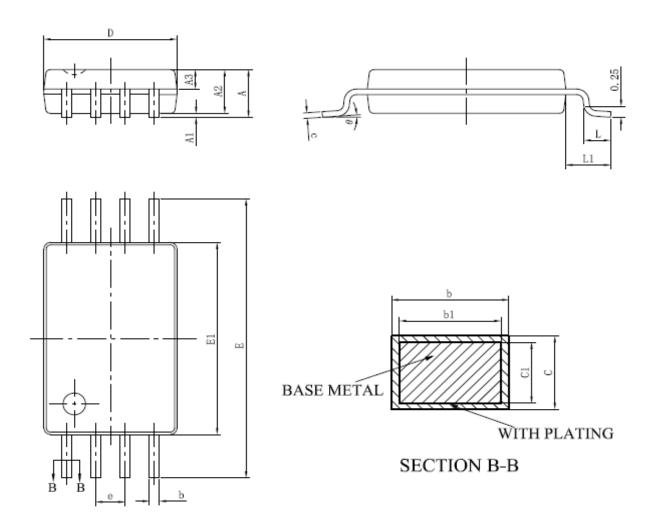


Figure 1 Normalized Maximum Transient Thermal Impedance



SSF8822

Mechanical Data:



Symbol	Dimension I	n Millimeters	Dimension In Inches		
Symbol	Min	Max	Min	Max	
D	2.800	3.200	0.110	0.126	
E	6.200	6.600	0.244	0.260	
b	0.210	0.280	0.008	0.011	
С	0.130	0.190	0.005	0.007	
E1	4.200	4.600	0.165	0.181	
A	-	1.200	-	0.047	
A2	0.850	1.150	0.033	0.045	
A1	0.050	0.150	0.002	0.006	
е	0.65 (BSC)		0.026	(BSC)	
L	0.450	0.750	0.018	0.030	
Н	0.25 TYP		0.01	TYP	
θ	1 ⁰	8 ⁰	1 ⁰	80	



Ordering and Marking Information

Device Marking	: SSF8822	
	Package (Available)	
	TSSOP-8	
	Operating Temperature Range	
	C : -55 to 150 °C	

Devices per Unit

Package	Units/	Tapes/	Units/	Inner Boxes/	Units/
Type	Tape	Inner Box	Inner Box	Carton Box	Carton Box
TSSOP-8	3000	2	6000	8	48000

Reliability Test Program

Test Item	Conditions	Duration	Sample Size
High	T _j =125℃ to 150℃ @	168 hours	3 lots x 77 devices
Temperature	80% of Max	500 hours	
Reverse	V _{DSS} /V _{CES} /VR	1000 hours	
Bias(HTRB)			
High	T _j =150℃@ 100% of	168 hours	3 lots x 77 devices
Temperature	Max V _{GSS}	500 hours	
Gate		1000 hours	
Bias(HTGB)			



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Customer Service Worldwide Sales and Service: Sales@silikron.com Technical Support: Technical@silikron.com Suzhou Silikron Semiconductor Corp. TEL: (86-512) 62560688 FAX: (86-512) 65160705 E-mail: Sales@silikron.com